

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10532167	LABEYE ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
DAVID CHONG	1797	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
359	321	9/23/08	DC
435	7.5	9/23/08	DC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Searched inventor in PALM	9/23/08	DC
Searched 359/321, 435/7.5 narrowed by keyword (see EAST search history)	9/23/08	DC
Searched databases USPAT, USPGPUB, EPO, JPO and DERWENT (see EAST search history)	9/23/08	DC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>